

Oral Presentation

[OLED6]OLED Advanced Technologies

Chair: Yoshimasa Sakai (MITSUBISHI CHEMICAL)

Co-Chair: Sukekazu Aratani (Samsung Electronics)

Fri. Nov 29, 2019 9:00 AM - 10:15 AM Room 204 (2F)

9:20 AM - 9:40 AM

[OLED6-2]Ultra High Resolution Imaging Light Measurement Device for Subpixel Metrology of μ -LEDs and OLED-Displays

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Keywords: μ -LED, subpixel metrology, ultra high resolution, display testing, light measurement device

We present ultra-high resolution measurements of (Micro-) OLED displays for subpixel metrology in display production and laboratories. A 150 megapixel camera merged with a high-end spectroradiometer allows for one-shot subpixel analysis of complete displays with spectroradiometric accuracy. An integrated pixel-shifter increases resolution to effectively 600 megapixels.